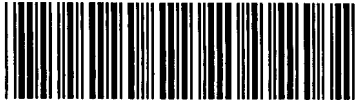


<b>Search Notes</b>  	<b>Application/Control No.</b>  10501315	<b>Applicant(s)/Patent Under Reexamination</b>  TO, BAN CHIN
	<b>Examiner</b>  Makiya, David J	<b>Art Unit</b>  2885

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
362	365	9/25/2007	DJM

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Search in EAST attached	9/25/2007	DJM
362/147,148,150	9/25/2007	DJM

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>